



REVISIONS			
REV.	DATE	DESCRIPTION	APD
E	31-05-16	Add cover	
Specification			
Item No.	SL-532-70-100		
Wavelength	532nm		
EFL	100mm		
BFL	105.98mm		
WD	98.98mm		
Scan angle	±25°		
Scan length	98mm		
Scan field	70mm×70mm		
Input beam EP	14mm		
M1-M2	15mm		
M2-lens center	18mm		
M2-mount edge	10.54mm		
Center spot size(1/e2)	9μm		
Edge spot size(1/e2)	15μm		
Outer diameter D	89mm		
Thread	M85×1		
Total length	49mm		
With protective window	Yes		
Transmission	>95%		
Series No.			

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	SURFACE: Black Anodize	DRAWN	YangYong	31-05-16	
	MATERIAL: AL	CHECKED			DWG. NO. SL022 REV. E
	UNIT: mm	SL-532-70-100			
SCALE:	SHEET: 1 OF 1				